Intel - 5AGZME7K2F40I3LN Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	21225
Number of Logic Elements/Cells	450000
Total RAM Bits	40249344
Number of I/O	674
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agzme7k2f40i3ln

Symbol	Description	Condition (V)	Calibration Accuracy			Unit
			–I3, –C4	–I5, –C5	–C6	
60-Ω and 120-Ω R_T	Internal parallel termination with calibration (60-Ω and 120-Ω setting)	V_{CCIO} = 1.2	−10 to +40	−10 to +40	−10 to +40	%
25-Ω $R_{S\_left\_shift}$	Internal left shift series termination with calibration (25-Ω $R_{S\_left\_shift}$ setting)	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	±15	±15	±15	%

OCT Without Calibration Resistance Tolerance Specifications

Table 1-9: OCT Without Calibration Resistance Tolerance Specifications for Arria V Devices

This table lists the Arria V OCT without calibration resistance tolerance to PVT changes.

Symbol	Description	Condition (V)	ResistanceTolerance			Unit
			–I3, –C4	–I5, –C5	–C6	
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 3.0, 2.5	±30	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8, 1.5	±30	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.2	±35	±50	±50	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 3.0, 2.5	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8, 1.5	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2	±35	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCIO} = 2.5	±25	±40	±40	%

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL}(14) (mA)	I_{OH}(14) (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
HSTL-15 Class II	—	V_{REF} – 0.1	V_{REF} + 0.1	—	V_{REF} – 0.2	V_{REF} + 0.2	0.4	V_{CCIO} – 0.4	16	–16
HSTL-12 Class I	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} – 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} – 0.08	V_{REF} + 0.08	V_{CCIO}+ 0.15	V_{REF} – 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	16	–16
HSUL-12	—	V_{REF} – 0.13	V_{REF} + 0.13	—	V_{REF} – 0.22	V_{REF} + 0.22	0.1 × V_{CCIO}	0.9 × V_{CCIO}	—	—

Differential SSTL I/O Standards

Table 1-17: Differential SSTL I/O Standards for Arria V Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V_{CCIO} + 0.6	V_{CCIO}/2 – 0.2	—	V_{CCIO}/2 + 0.2	0.62	V_{CCIO} + 0.6
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO} + 0.6	V_{CCIO}/2 – 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO} + 0.6
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	(15)	V_{CCIO}/2 – 0.15	—	V_{CCIO}/2 + 0.15	2($V_{IH(AC)}$ – V_{REF})	2($V_{IL(AC)}$ – V_{REF})
SSTL-135	1.283	1.35	1.45	0.18	(15)	V_{CCIO}/2 – 0.15	V_{CCIO}/2	V_{CCIO}/2 + 0.15	2($V_{IH(AC)}$ – V_{REF})	2($V_{IL(AC)}$ – V_{REF})

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(14) To meet the I_{OL} and I_{OH} specifications, you must set the current strength settings accordingly. For example, to meet the SSTL15CI specification (8 mA), you should set the current strength settings to 8 mA. Setting at lower current strength may not meet the I_{OL} and I_{OH} specifications in the datasheet.

(15) The maximum value for $V_{SWING(DC)}$ is not defined. However, each single-ended signal needs to be within the respective single-ended limits ($V_{IH(DC)}$ and $V_{IL(DC)}$).

Symbol/Description	Condition	Transceiver Speed Grade 4			Transceiver Speed Grade 6			Unit
		Min	Typ	Max	Min	Typ	Max	
Minimum differential eye opening at the receiver serial input pins(30)	—	100	—	—	100	—	—	mV
V_{ICM} (AC coupled)	—	—	0.7/0.75/ 0.8(31)	—	—	0.7/0.75/ 0.8 (31)	—	mV
V_{ICM} (DC coupled)	≤ 3.2Gbps(32)	670	700	730	670	700	730	mV
Differential on-chip termination resistors	85-Ω setting	—	85	—	—	85	—	Ω
	100-Ω setting	—	100	—	—	100	—	Ω
	120-Ω setting	—	120	—	—	120	—	Ω
	150-Ω setting	—	150	—	—	150	—	Ω
t_{LTR}(33)	—	—	—	10	—	—	10	µs
t_{LTD}(34)	—	4	—	—	4	—	—	µs
t_{LTD_manual}(35)	—	4	—	—	4	—	—	µs
$t_{LTR\_LTD\_manual}$(36)	—	15	—	—	15	—	—	µs
Programmable ppm detector(37)	—	±62.5, 100, 125, 200, 250, 300, 500, and 1000						ppm

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(30) The differential eye opening specification at the receiver input pins assumes that you have disabled the **Receiver Equalization** feature. If you enable the **Receiver Equalization** feature, the receiver circuitry can tolerate a lower minimum eye opening, depending on the equalization level.

(31) The AC coupled V_{ICM} = 700 mV for Arria V GX and SX in PCIe mode only. The AC coupled V_{ICM} = 750 mV for Arria V GT and ST in PCIe mode only.

(32) For standard protocol compliance, use AC coupling.

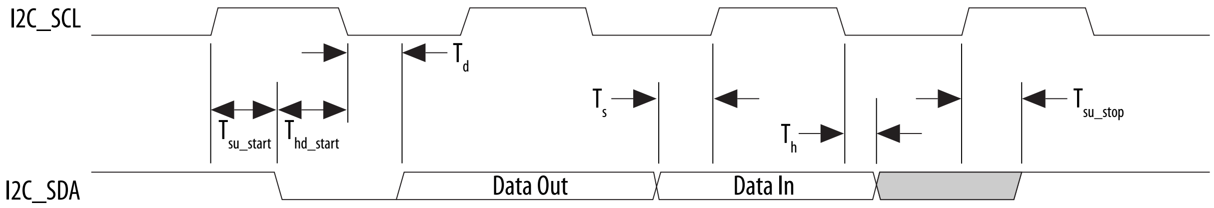
(33) t_{LTR} is the time required for the receive CDR to lock to the input reference clock frequency after coming out of reset.

(34) t_{LTD} is time required for the receiver CDR to start recovering valid data after the `rx_is_lockedtodata` signal goes high.

(35) t_{LTD_manual} is the time required for the receiver CDR to start recovering valid data after the `rx_is_lockedtodata` signal goes high when the CDR is functioning in the manual mode.

(36) $t_{LTR\_LTD\_manual}$ is the time the receiver CDR must be kept in lock to reference (LTR) mode after the `rx_is_lockedtoref` signal goes high when the CDR is functioning in the manual mode.

Figure 1-16: I^2C Timing Diagram



NAND Timing Characteristics

Table 1-60: NAND ONFI 1.0 Timing Requirements for Arria V Devices

The NAND controller supports Open NAND FLASH Interface (ONFI) 1.0 Mode 5 timing as well as legacy NAND devices. This table lists the requirements for ONFI 1.0 mode 5 timing. The HPS NAND controller can meet this timing by programming the `C4` output of the main HPS PLL and timing registers provided in the NAND controller.

Symbol	Description	Min	Max	Unit
T_{wp}(89)	Write enable pulse width	10	—	ns
T_{wh}(89)	Write enable hold time	7	—	ns
T_{rp}(89)	Read enable pulse width	10	—	ns
T_{reh}(89)	Read enable hold time	7	—	ns
T_{clesu}(89)	Command latch enable to write enable setup time	10	—	ns
T_{cleh}(89)	Command latch enable to write enable hold time	5	—	ns
T_{cesu}(89)	Chip enable to write enable setup time	15	—	ns
T_{ceh}(89)	Chip enable to write enable hold time	5	—	ns
T_{alesu}(89)	Address latch enable to write enable setup time	10	—	ns
T_{aleh}(89)	Address latch enable to write enable hold time	5	—	ns
T_{dsu}(89)	Data to write enable setup time	10	—	ns

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(89) Timing of the NAND interface is controlled through the NAND configuration registers.

FPP Configuration Timing when DCLK-to-DATA[] >1

Table 1-67: FPP Timing Parameters When DCLK-to-DATA[] Ratio is >1 for Arria V Devices

Use these timing parameters when you use the decompression and design security features.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CF2CD}	`nCONFIG` low to `CONF_DONE` low	—	600	ns
t_{CF2ST0}	`nCONFIG` low to `nSTATUS` low	—	600	ns
t_{CFG}	`nCONFIG` low pulse width	2	—	µs
t_{STATUS}	`nSTATUS` low pulse width	268	1506(98)	µs
t_{CF2ST1}	`nCONFIG` high to `nSTATUS` high	—	1506(99)	µs
t_{CF2CK}(100)	`nCONFIG` high to first rising edge on `DCLK`	1506	—	µs
t_{ST2CK}(100)	`nSTATUS` high to first rising edge of `DCLK`	2	—	µs
t_{DSU}	`DATA[]` setup time before rising edge on `DCLK`	5.5	—	ns
t_{DH}	`DATA[]` hold time after rising edge on `DCLK`	$N - 1/f_{DCLK}$(101)	—	s
t_{CH}	`DCLK` high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	`DCLK` low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	`DCLK` period	$1/f_{MAX}$	—	s
f_{MAX}	`DCLK` frequency (FPP ×8/ ×16)	—	125	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	`CONF_DONE` high to user mode(102)	175	437	µs

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(98) This value can be obtained if you do not delay configuration by extending the `nCONFIG` or `nSTATUS` low pulse width.

(99) This value can be obtained if you do not delay configuration by externally holding `nSTATUS` low.

(100) If `nSTATUS` is monitored, follow the t_{ST2CK} specification. If `nSTATUS` is not monitored, follow the t_{CF2CK} specification.

(101) N is the `DCLK`-to-`DATA[]` ratio and f_{DCLK} is the `DCLK` frequency of the system.

(102) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

Variant	Member Code	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits)
Arria V GX	A1	71,015,712	439,960
	A3	71,015,712	439,960
	A5	101,740,800	446,360
	A7	101,740,800	446,360
	B1	137,785,088	457,368
	B3	137,785,088	457,368
	B5	185,915,808	463,128
	B7	185,915,808	463,128
Arria V GT	C3	71,015,712	439,960
	C7	101,740,800	446,360
	D3	137,785,088	457,368
	D7	185,915,808	463,128
Arria V SX	B3	185,903,680	450,968
	B5	185,903,680	450,968
Arria V ST	D3	185,903,680	450,968
	D5	185,903,680	450,968

Minimum Configuration Time Estimation

Table 1-73: Minimum Configuration Time Estimation for Arria V Devices

The estimated values are based on the configuration `.rbf` sizes in Uncompressed .rbf Sizes for Arria V Devices table.

Date	Version	Changes
July 2014	3.8	• Added a note in Table 3, Table 4, and Table 5: The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements. • Updated V_{CC_HPS} specification in Table 5. • Added a note in Table 19: Differential inputs are powered by V_{CCPD} which requires 2.5 V. • Updated "Minimum differential eye opening at the receiver serial input pins" specification in Table 20 and Table 21. • Updated description in “HPS PLL Specifications” section. • Updated VCO range maximum specification in Table 39. • Updated T_d and T_h specifications in Table 45. • Added T_h specification in Table 47 and Figure 13. • Updated a note in Figure 20, Figure 21, and Figure 23 as follows: Do not leave DCLK floating after configuration. DCLK is ignored after configuration is complete. It can toggle high or low if required. • Removed “Remote update only in AS mode” specification in Table 58. • Added DCLK device initialization clock source specification in Table 60. • Added description in “Configuration Files” section: The IOCSR `.rbf` size is specifically for the Configuration via Protocol (CvP) feature. • Removed $f_{MAX\_RU\_CLK}$ specification in Table 63.
February 2014	3.7	• Updated $V_{CCRSTCLK\_HPS}$ maximum specification in Table 1. • Added $V_{CC\_AUX\_SHARED}$ specification in Table 1.
December 2013	3.6	• Added “HPS PLL Specifications”. • Added Table 24, Table 39, and Table 40. • Updated Table 1, Table 3, Table 5, Table 19, Table 20, Table 21, Table 38, Table 41, Table 42, Table 43, Table 44, Table 45, Table 46, Table 47, Table 48, Table 49, Table 50, Table 51, Table 55, Table 56, and Table 59. • Updated Figure 7, Figure 13, Figure 15, Figure 16, and Figure 19. • Removed table: GPIO Pulse Width for Arria V Devices.

Date	Version	Changes
August 2013	3.5	• Removed "Pending silicon characterization" note in Table 29. • Updated Table 25.
August 2013	3.4	• Removed Preliminary tags for Table 1, Table 2, Table 3, Table 4, Table 5, Table 6, Table 7, Table 9, Table 12, Table 13, Table 14, Table 15, Table 16, Table 17, Table 18, Table 19, Table 20, Table 21, Table 22, Table 23, Table 24, Table 25, Table 26, Table 27, Table 28, Table 29, Table 30, Table 31, Table 35, Table 36, Table 51, Table 53, Table 54, Table 55, Table 56, Table 57, Table 60, Table 62, and Table 64. • Updated Table 1, Table 3, Table 11, Table 19, Table 20, Table 21, Table 22, Table 25, and Table 29.
June 2013	3.3	Updated Table 20, Table 21, Table 25, and Table 38.
May 2013	3.2	• Added Table 37. • Updated Figure 8, Figure 9, Figure 20, Figure 22, and Figure 23. • Updated Table 1, Table 5, Table 10, Table 13, Table 19, Table 20, Table 21, Table 23, Table 29, Table 39, Table 40, Table 46, Table 56, Table 57, Table 60, and Table 64. • Updated industrial junction temperature range for –I3 speed grade in "PLL Specifications" section.
March 2013	3.1	• Added HPS reset information in the "HPS Specifications" section. • Added Table 60. • Updated Table 1, Table 3, Table 17, Table 20, Table 29, and Table 59. • Updated Figure 21.

Date	Version	Changes
June 2012	2.0	• Updated for the Quartus II software v12.0 release: • Restructured document. • Updated “Supply Current and Power Consumption” section. • Updated Table 20, Table 21, Table 24, Table 25, Table 26, Table 35, Table 39, Table 43, and Table 52. • Added Table 22, Table 23, and Table 33. • Added Figure 1–1 and Figure 1–2. • Added “Initialization” and “Configuration Files” sections.
February 2012	1.3	• Updated Table 2–1. • Updated Transceiver-FPGA Fabric Interface rows in Table 2–20. • Updated V_{CCP} description.
December 2011	1.2	Updated Table 2–1 and Table 2–3.
November 2011	1.1	• Updated Table 2–1, Table 2–19, Table 2–26, and Table 2–36. • Added Table 2–5. • Added Figure 2–4.
August 2011	1.0	Initial release.

Lower number refers to faster speed grade.

L = Low power devices.

Transceiver Speed Grade	Core Speed Grade			
	C3	C4	I3L	I4
2	Yes	—	Yes	—
3	—	Yes	—	Yes

Absolute Maximum Ratings

Absolute maximum ratings define the maximum operating conditions for Arria V GZ devices. The values are based on experiments conducted with the devices and theoretical modeling of breakdown and damage mechanisms. The functional operation of the device is not implied for these conditions.

Caution: Conditions other than those listed in the following table may cause permanent damage to the device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse effects on the device.

Table 2-2: Absolute Maximum Ratings for Arria V GZ Devices

Symbol	Description	Minimum	Maximum	Unit
V_{CC}	Power supply for core voltage and periphery circuitry	–0.5	1.35	V
V_{CCPT}	Power supply for programmable power technology	–0.5	1.8	V
V_{CCPGM}	Power supply for configuration pins	–0.5	3.9	V
V_{CC_AUX}	Auxiliary supply for the programmable power technology	–0.5	3.4	V
V_{CCBAT}	Battery back-up power supply for design security volatile key register	–0.5	3.9	V
V_{CCPD}	I/O pre-driver power supply	–0.5	3.9	V
V_{CCIO}	I/O power supply	–0.5	3.9	V
V_{CCD_FPLL}	PLL digital power supply	–0.5	1.8	V
V_{CCA_FPLL}	PLL analog power supply	–0.5	3.4	V

Symbol	Description	Condition	Minimum[114]	Typical	Maximum [114]	Unit
V_I	DC input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C
t_{RAMP}	Power supply ramp time	Standard POR	200 µs	—	100 ms	—
		Fast POR	200 µs	—	4 ms	—

Recommended Transceiver Power Supply Operating Conditions

Table 2-6: Recommended Transceiver Power Supply Operating Conditions for Arria V GZ Devices

Symbol	Description	Minimum [118]	Typical	Maximum[118]	Unit
V_{CCA_GXBL} [119], [120]	Transceiver channel PLL power supply (left side)	2.85	3.0	3.15	V
		2.375	2.5	2.625	
V_{CCA_GXBR} [119], [120]	Transceiver channel PLL power supply (right side)	2.85	3.0	3.15	V
		2.375	2.5	2.625	
V_{CCHIP_L}	Transceiver hard IP power supply (left side)	0.82	0.85	0.88	V
V_{CCHSSI_L}	Transceiver PCS power supply (left side)	0.82	0.85	0.88	V
V_{CCHSSI_R}	Transceiver PCS power supply (right side)	0.82	0.85	0.88	V

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[114] The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

[118] This value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

[119] This supply must be connected to 3.0 V if the CMU PLL, receiver CDR, or both, are configured at a base data rate > 6.5 Gbps. Up to 6.5 Gbps, you can connect this supply to either 3.0 V or 2.5 V.

[120] When using ATX PLLs, the supply must be 3.0 V.

Symbol	Description	Conditions	Resistance Tolerance		Unit
			C3, I3L	C4, I4	
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCIO} = 2.5 V	±25	±25	%

Figure 2-1: OCT Variation Without Re-Calibration for Arria V GZ Devices

$$R_{OCT} = R_{SCAL}\left(1 + \left(\frac{dR}{dT} \times \triangle T\right) \pm \left(\frac{dR}{dV} \times \triangle V\right)\right)$$

Notes:
1. The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.
2. R_{SCAL} is the OCT resistance value at power-up.
3. ΔT is the variation of temperature with respect to the temperature at power-up.
4. ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
5. dR/dT is the percentage change of R_{SCAL} with temperature.
6. dR/dV is the percentage change of R_{SCAL} with voltage.

Table 2-12: OCT Variation after Power-Up Calibration for Arria V GZ Devices

Valid for a V_{CCIO} range of ±5% and a temperature range of 0° to 85°C.

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{ol} (mA)	I_{oh} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-18 Class II	–0.3	$V_{REF} - 0.125$	$V_{REF} + 0.125$	$V_{CCIO} + 0.3$	$V_{REF} - 0.25$	$V_{REF} + 0.25$	0.28	$V_{CCIO} - 0.28$	13.4	–13.4
SSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	8	–8
SSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.175$	$V_{REF} + 0.175$	$0.2 \times V_{CCIO}$	$0.8 \times V_{CCIO}$	16	–16
SSTL-135 Class I, II	—	$V_{REF} - 0.09$	$V_{REF} + 0.09$	—	$V_{REF} - 0.16$	$V_{REF} + 0.16$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—
SSTL-125 Class I, II	—	$V_{REF} - 0.85$	$V_{REF} + 0.85$	—	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—
SSTL-12 Class I, II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.2 * V_{CCIO}$	$0.8 * V_{CCIO}$	—	—
HSTL-18 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	–8
HSTL-18 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	–16
HSTL-15 Class I	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	8	–8
HSTL-15 Class II	—	$V_{REF} - 0.1$	$V_{REF} + 0.1$	—	$V_{REF} - 0.2$	$V_{REF} + 0.2$	0.4	$V_{CCIO} - 0.4$	16	–16
HSTL-12 Class I	–0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	8	–8
HSTL-12 Class II	–0.15	$V_{REF} - 0.08$	$V_{REF} + 0.08$	$V_{CCIO} + 0.15$	$V_{REF} - 0.15$	$V_{REF} + 0.15$	$0.25 \times V_{CCIO}$	$0.75 \times V_{CCIO}$	16	–16
HSUL-12	—	$V_{REF} - 0.13$	$V_{REF} + 0.13$	—	$V_{REF} - 0.22$	$V_{REF} + 0.22$	$0.1 \times V_{CCIO}$	$0.9 \times V_{CCIO}$	—	—

Symbol/Description	Conditions	Transceiver Speed Grade 2			Transceiver Speed Grade 3			Unit
		Min	Typ	Max	Min	Typ	Max	
Transmitter REFCLK Phase Noise (622 MHz) (141)	100 Hz	—	—	-70	—	—	-70	dBc/Hz
	1 kHz	—	—	-90	—	—	-90	dBc/Hz
	10 kHz	—	—	-100	—	—	-100	dBc/Hz
	100 kHz	—	—	-110	—	—	-110	dBc/Hz
	≥1 MHz	—	—	-120	—	—	-120	dBc/Hz
Transmitter REFCLK Phase Jitter (100 MHz) (142)	10 kHz to 1.5 MHz (PCIe)	—	—	3	—	—	3	ps (rms)
R_{REF}	—	—	1800 ±1%	—	—	1800 ±1%	—	Ω

Related Information

Arria V Device Overview

For more information about device ordering codes.

Transceiver Clocks

Table 2-23: Transceiver Clocks Specifications for Arria V GZ Devices

Speed grades shown refer to the PMA Speed Grade in the device ordering code. The maximum data rate could be restricted by the Core/PCS speed grade. Contact your Altera Sales Representative for the maximum data rate specifications in each speed grade combination offered. For more information about device ordering codes, refer to the *Arria V Device Overview*.

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(141) To calculate the REFCLK phase noise requirement at frequencies other than 622 MHz, use the following formula: REFCLK phase noise at f(MHz) = REFCLK phase noise at 622 MHz + 20*log(f/622).

(142) To calculate the REFCLK rms phase jitter requirement for PCIe at reference clock frequencies other than 100 MHz, use the following formula: REFCLK rms phase jitter at f(MHz) = REFCLK rms phase jitter at 100 MHz × 100/f.

Symbol	Conditions	C3, I3L			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
f_{HSCLK_in} (input clock frequency) True Differential I/O Standards (179)	Clock boost factor W = 1 to 40 (180)	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 (180)	5	—	625	5	—	525	MHz
f_{HSCLK_in} (input clock frequency) Single Ended I/O Standards	Clock boost factor W = 1 to 40 (180)	5	—	420	5	—	420	MHz
f_{HSCLK_OUT} (output clock frequency)	—	5	—	625 (181)	5	—	525 (181)	MHz

Transmitter High-Speed I/O Specifications

Table 2-40: Transmitter High-Speed I/O Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

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(179) This only applies to DPA and soft-CDR modes.

(180) Clock Boost Factor (W) is the ratio between the input data rate to the input clock rate.

(181) This is achieved by using the LVDS clock network.

Symbol	Conditions	C3, I3L			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
True Differential I/O Standards - f_{HSDR} (data rate)	SERDES factor J = 3 to 10 (182), (183)	(184)	—	1250	(184)	—	1050	Mbps
	SERDES factor J ≥ 4 LVDS TX with DPA (185), (186), (187), (188)	(184)	—	1600	(184)	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(184)	—	(189)	(184)	—	(189)	Mbps
	SERDES factor J = 1, uses SDR Register	(184)	—	(189)	(184)	—	(189)	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Networks - f_{HSDR} (data rate) (190)	SERDES factor J = 4 to 10 (191)	(184)	—	840	(184)	—	840	Mbps

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(182) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.

(183) The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design dependent and requires timing analysis.

(184) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

(185) Arria V GZ RX LVDS will need DPA. For Arria V GZ TX LVDS, the receiver side component must have DPA.

(186) Requires package skew compensation with PCB trace length.

(187) Do not mix single-ended I/O buffer within LVDS I/O bank.

(188) Chip-to-chip communication only with a maximum load of 5 pF.

(189) The maximum ideal data rate is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.

(190) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.

(191) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

Symbol	Conditions	C3, I3L			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
True Differential I/O Standards - $f_{HSDRDPA}$ (data rate)	SERDES factor J = 3 to 10 (192), (193), (194), (195), (196), (197)	150	—	1250	150	—	1050	Mbps
	SERDES factor J ≥ 4 LVDS RX with DPA (193), (195), (196), (197)	150	—	1600	150	—	1250	Mbps
	SERDES factor J = 2, uses DDR Registers	(198)	—	(199)	(198)	—	(199)	Mbps
	SERDES factor J = 1, uses SDR Register	(198)	—	(199)	(198)	—	(199)	Mbps
f_{HSDR} (data rate)	SERDES factor J = 3 to 10	(198)	—	(200)	(198)	—	(200)	Mbps
	SERDES factor J = 2, uses DDR Registers	(198)	—	(199)	(198)	—	(199)	Mbps
	SERDES factor J = 1, uses SDR Register	(198)	—	(199)	(198)	—	(199)	Mbps

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(192) The F_{MAX} specification is based on the fast clock used for serial data. The interface F_{MAX} is also dependent on the parallel clock domain which is design dependent and requires timing analysis.

(193) Arria V GZ RX LVDS will need DPA. For Arria V GZ TX LVDS, the receiver side component must have DPA.

(194) Arria V GZ LVDS serialization and de-serialization factor needs to be x4 and above.

(195) Requires package skew compensation with PCB trace length.

(196) Do not mix single-ended I/O buffer within LVDS I/O bank.

(197) Chip-to-chip communication only with a maximum load of 5 pF.

(198) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

(199) The maximum ideal data rate is the SERDES factor (J) x the PLL maximum output frequency (fOUT) provided you can close the design timing and the signal integrity simulation is clean.

(200) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and receiver sampling margin to determine the maximum data rate supported.

Table 2-55: DCLK-to-DATA[] Ratio for Arria V GZ Devices

Depending on the `DCLK-to-DATA[]` ratio, the host must send a `DCLK` frequency that is r times the data rate in bytes per second (Bps), or words per second (Wps). For example, in FPP ×16 when the `DCLK-to-DATA[]` ratio is 2, the `DCLK` frequency must be 2 times the data rate in Wps. Arria V GZ devices use the additional clock cycles to decrypt and decompress the configuration data.

Configuration Scheme	Decompression	Design Security	DCLK-to-DATA[] Ratio
FPP ×8	Disabled	Disabled	1
	Disabled	Enabled	1
	Enabled	Disabled	2
	Enabled	Enabled	2
FPP ×16	Disabled	Disabled	1
	Disabled	Enabled	2
	Enabled	Disabled	4
	Enabled	Enabled	4
FPP ×32	Disabled	Disabled	1
	Disabled	Enabled	4
	Enabled	Disabled	8
	Enabled	Enabled	8

Symbol	Parameter	Minimum	Maximum	Unit
t_{CD2CU}	`CONF_DONE` high to `CLKUSR` enabled	4 × maximum `DCLK` period	—	—
t_{CD2UMC}	`CONF_DONE` high to user mode with `CLKUSR` option on	t_{CD2CU} + (8576 × `CLKUSR` period) (209)	—	—

Related Information

- **DCLK-to-DATA[] Ratio (r) for FPP Configuration** on page 2-57
- **Configuration, Design Security, and Remote System Upgrades in Arria V Devices**

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(208) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

(209) To enable the `CLKUSR` pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the "Initialization" section of the *Configuration, Design Security, and Remote System Upgrades in Arria V Devices* chapter.